

<b>Search Notes</b> 	<b>Application/Control No.</b>	<b>Applicant(s)/Patent under Reexamination</b>	
	10/077,847	LEE ET AL.	
	<b>Examiner</b> Vincent T. Tran	<b>Art Unit</b> 2115	

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
365	185	11/2/2004	VT
713	300 310 192	11/2/2004	VT
358	444	3/15/2006	VT